

ZXMN6A25N8 60V SO8 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)
60	0.050 @ V _{GS} =10V	7.0
	0.070 @ V _{GS} =4.5V	



Description

This new generation Trench MOSFET from Zetex features low on-resistance and fast switching, making it ideal for high efficiency power management applications.

Features

- Low on-resistance
- Fast switching speed
- Low gate drive
- SO8 package

Applications

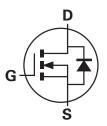
- DC-DC Converters
- Power management functions
- Disconnect switches
- Motor control

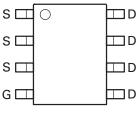
Ordering information

Device	Reel size	Tape width	Quantity
	(inches)	(mm)	per reel
ZXMN6A25N8TA	7	12	500

Device marking

ZXMN6A25





Top view

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain-Source voltage	V _{DSS}	60	V
Gate-Source voltage	V _{GS}	± 20	V
Continuous Drain current @ V_{GS} = 10V; T_A =25°C (b)	ID	5.7	А
@ V _{GS} = 10V; T _A =70°C ^(D)		4.5	
@ V _{GS} = 10V; T _A =25°C ^(a)		4.3	
@ V _{GS} = 10V; T _L =25°C ^{(a)(d)}		7.0	
Pulsed Drain current ^(C)	I _{DM}	25.7	А
Continuous Source current (Body diode)	I _S	4.1	А
Pulsed Source current (Body diode) (c)	I _{SM}	25.7	А
Power dissipation at $T_A = 25 \degree C^{(a)}$	PD	1.56	W
Linear derating factor		12.5	mW/°C
Power dissipation at $T_A = 25 \circ C^{(b)}$	PD	2.8	W
Linear derating factor	_	22.2	mW/°C
Power dissipation at T_{L} =25°C ^(d)	PD	4.14	W
Linear derating factor		33.1	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to 150	°C

Thermal resistance

Parameter	Symbol	Value	Unit
Junction to ambient ^(a)	$R_{\theta JA}$	80	°C/W
Junction to ambient ^(b)	R _{0JA}	45	°C/W
Junction to lead ^(d)	$R_{\theta JL}$	30.2	°C/W

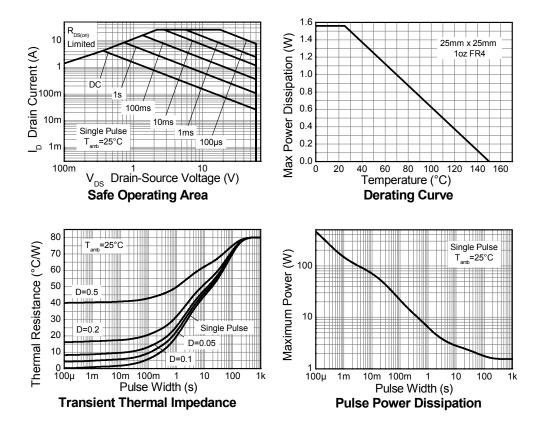
NOTES:

- (a) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) Mounted on FR4 PCB measured at t ≤ 10 sec.
(c) Repetitive rating on 25mm x 25mm FR4 PCB, D=0.02, pulse width 300us – pulse width limited by maximum junction temperature.

(d) Thermal resistance from junction to solder-point (at the end of the drain lead).

Thermal characteristics



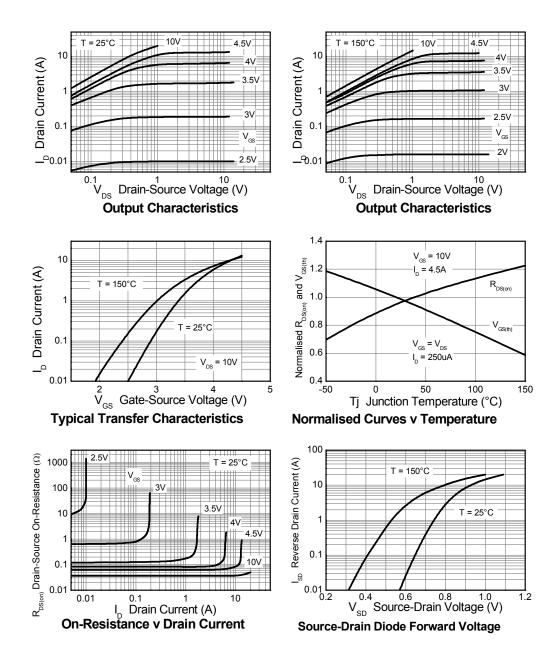
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-Source breakdown voltage	V _{(BR)DSS}	60			V	I _D =250μΑ, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			1.0	μA	V _{DS} =60V, V _{GS} =0V
Gate-Body leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-Source threshold voltage	V _{GS(th)}	1		3	V	$I_D=250\mu A, V_{DS}=V_{GS}$
Static Drain-Source on-state resistance ^(*)	R _{DS(on)}			0.050 0.070	Ω	V _{GS} = 10V, I _D = 3.6A V _{GS} = 4.5V, I _D = 3.0A
Forward Transconductance ^{(*) (†)}	9 _{fs}		10.2		S	V _{DS} = 15V, I _D = 4.5A
Dynamic ^(†)	1 1		•			
Input capacitance	C _{iss}		1063		pF	
Output capacitance	C _{oss}		104		pF	V _{DS} = 30V, V _{GS} =0V
Reverse transfer capacitance	C _{rss}		64		pF	f=1MHz
Switching ^{(‡) (†)}	1 1		•			
Turn-on-delay time	t _{d(on)}		3.8		ns	
Rise time	t _r		4.0		ns	V _{DD} = 30V, V _{GS} = 10V
Turn-off delay time	t _{d(off)}		26.2		ns	I _D = 1A
Fall time	t _f		10.6		ns	R _G ≅ 6.0Ω,
Gate charge	Qg		11.0		nC	V _{DS} = 30V, V _{GS} = 5V I _D = 4.5A
Total gate charge	Qg		20.4		nC	
Gate-Source charge	Q _{gs}		4.1		nC	V _{DS} = 30V, V _{GS} = 10V
Gate-Drain charge	Q _{gd}		5.1		nC	I _D = 4.5A
Source–Drain diode	0.		1	1	1	1
Diode forward voltage (*)	V _{SD}		0.85	0.95	V	I _S = 5.5A,V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		22.0		ns	
Reverse recovery charge ^(‡)	Q _{rr}		21.4		nC	I _S = 2.2A,di/dt=100A/μs

Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

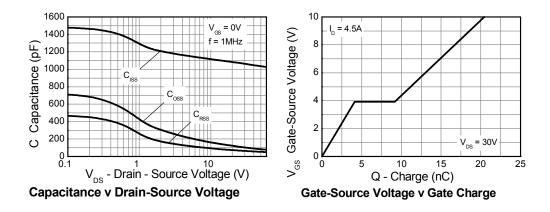
NOTES:

(*) Measured under pulsed conditions. Pulse width $\leq 300 \mu$ s; duty cycle $\leq 2\%$. (†)Switching characteristics are independent of operating junction temperature. (‡)For design aid only, not subject to production testing

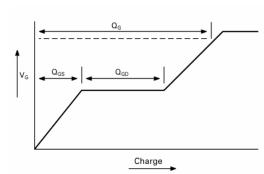
Typical characteristics



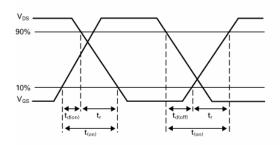
Typical characteristics



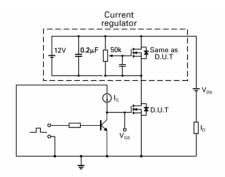
Test circuits



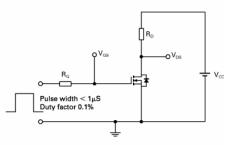
Basic gate charge waveform

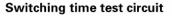


Switching time waveforms



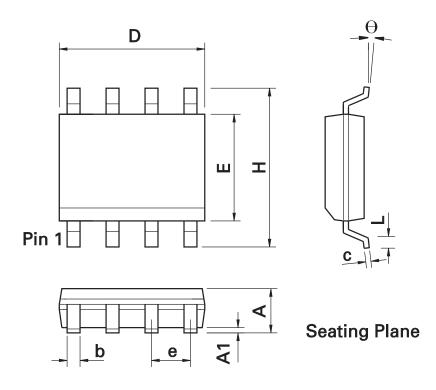
Gate charge test circuit





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Package outline SO8



SO8 Package Information

DIM	Inc	hes	Millin	neters	DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
А	0.053	0.069	1.35	1.75	е	0.050) BSC	1.27	BSC
A1	0.004	0.010	0.10	0.25	b	0.013	0.020	0.33	0.51
D	0.189	0.197	4.80	5.00	С	0.008	0.010	0.19	0.25
н	0.228	0.244	5.80	6.20	U	0°	8°	0°	8°
E	0.150	0.157	3.80	4.00	h	0.010	0.020	0.25	0.50
L	0.016	0.050	0.40	1.27	-	-	-	_	-

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Note: Controlling dimensions are in inches. Approximate dimensions are provided in millimeters

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"Last time buy (LTB)"	Device will be discontinued an	Device will be discontinued and last time buy period and delivery is in effect					
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Datasheet status key:							
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